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(12) **United States Design Patent** (10) **Patent No.:** **US D452,178 S**  
**Wai Ming et al.** (45) **Date of Patent:** **\*\* Dec. 18, 2001**

(54) **PROBE THERMOMETER**

L.L.C.

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(US)

(57) **CLAIM**

The ornamental design for a probe thermometer, as shown.

(73) Assignee: **Chaney Instrument Company**, Lake  
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**DESCRIPTION**

(\* ) Notice: This patent is subject to a terminal dis-  
claimer.

FIG. 1 is a perspective view of the probe thermometer  
showing our new design;

(\*\*) Term: **14 Years**

FIG. 2 is a right side elevation view of the probe thermom-  
eter shown in FIG. 1, the left side elevation view being a  
mirror image thereof;

(21) Appl. No.: **29/123,913**

FIG. 3 is a front elevation view of the probe thermometer of  
FIG. 1;

(22) Filed: **May 26, 2000**

FIG. 4 is a top plan view of the probe thermometer shown  
in FIG. 1;

(51) **LOC (7) Cl.** ..... **10-04**

FIG. 5 is a bottom plan view of the probe thermometer  
shown in FIG. 1;

(52) **U.S. Cl.** ..... **D10/57**

FIG. 6 is a back plan view of the probe thermometer shown  
in FIG. 1;

(58) **Field of Search** ..... D10/57; D7/653,  
D7/683; 30/129, 147, 148, 142, 150, 322,  
323; 294/55.5, 61; 374/141, 155, 184, 208-210

FIG. 7 is a perspective view of an alternate embodiment of  
the invention in which a portion of the probe of FIG. 1 is  
uncovered;

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

D. 236,254	*	8/1975	Ray	.....	D10/57
D. 236,814	*	9/1975	Sato	.....	D10/57
D. 257,428	*	10/1980	Manno	.....	D10/57
D. 268,991	*	5/1983	Bilgutay	.....	D10/57
D. 297,819	*	9/1988	Cacciatore	.....	D10/57
D. 439,809	*	4/2001	Ming et al.	.....	D10/57 X

FIG. 8 is a perspective view of an alternate embodiment of  
the invention in which a portion of the probe of FIG. 1 is  
uncovered;

\* cited by examiner

FIG. 9 is a right side elevation view of the probe thermom-  
eter of FIG. 7, with the left side elevation view being a  
mirror image thereof;

*Primary Examiner*—Antoine Duval Davis

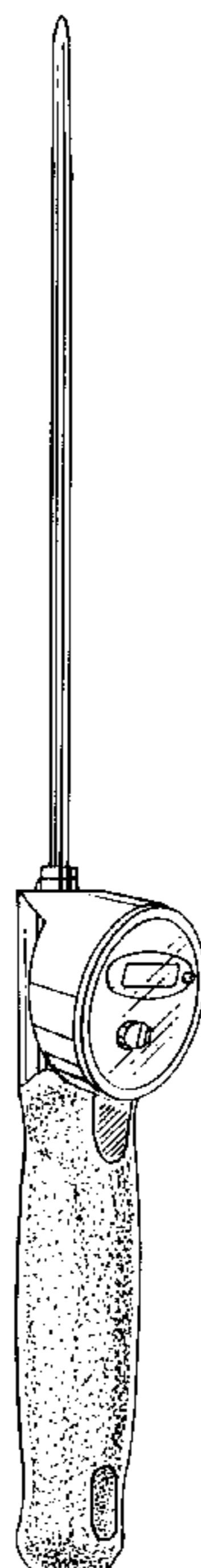
(74) *Attorney, Agent, or Firm*—Michael Best & Friedrich,

FIG. 10 is a front elevation view of the probe thermometer  
of FIG. 7;

FIG. 11 is a top plan view of the probe thermometer of FIG.  
7; and,

FIG. 12 is a back elevation of the probe thermometer of FIG.  
7.

**1 Claim, 4 Drawing Sheets**



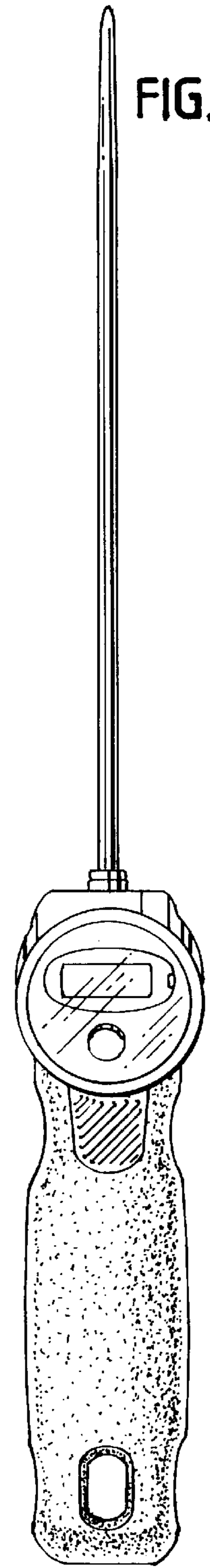
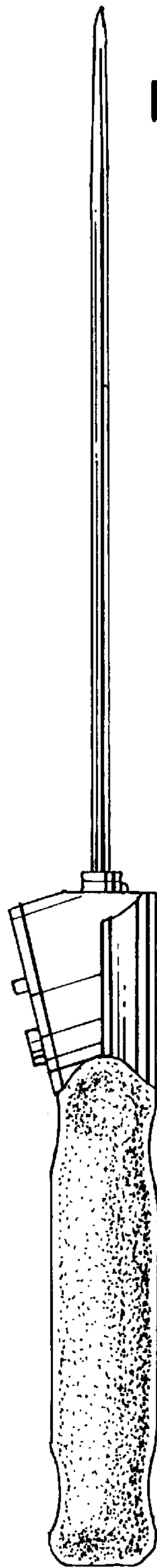
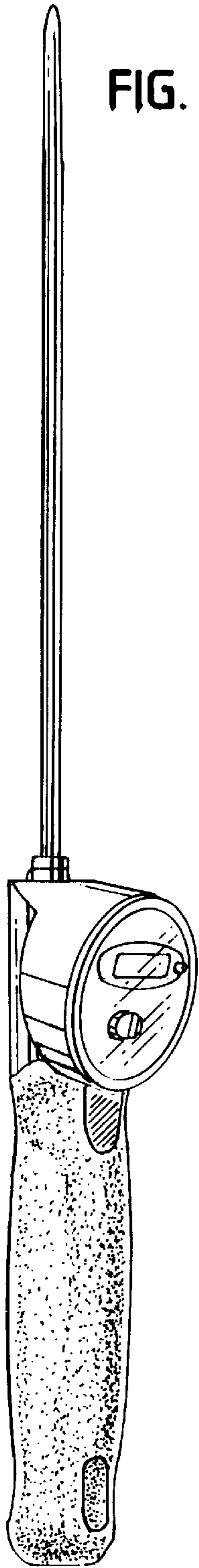


FIG. 4

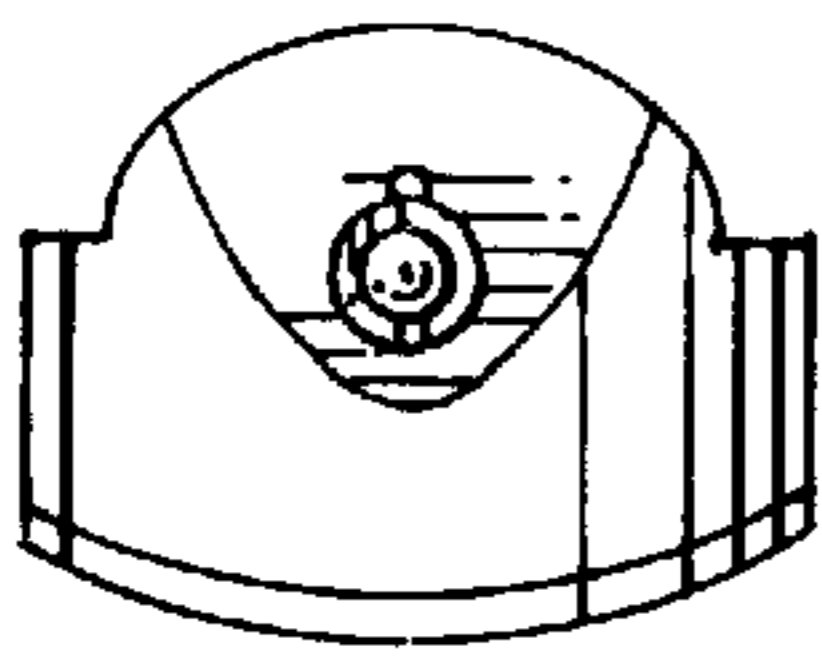


FIG. 5

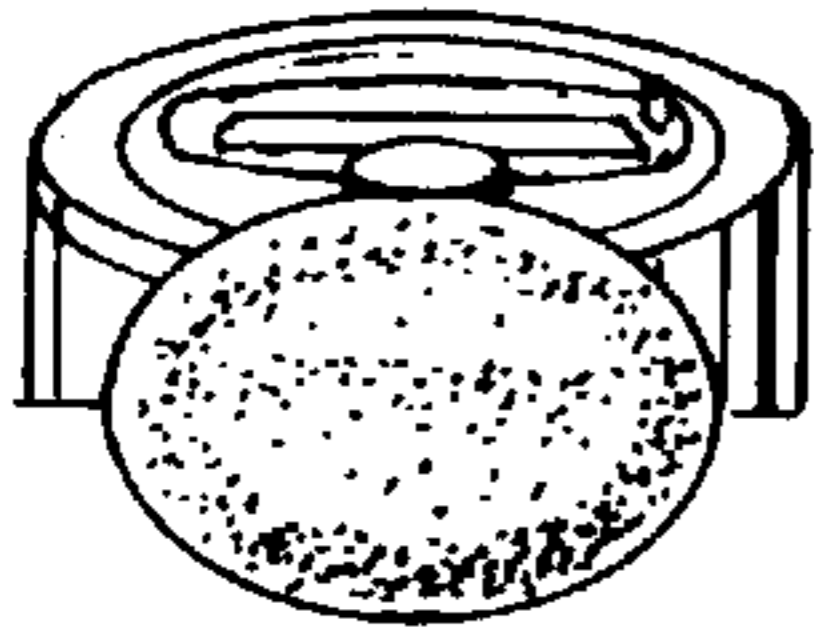


FIG. 6

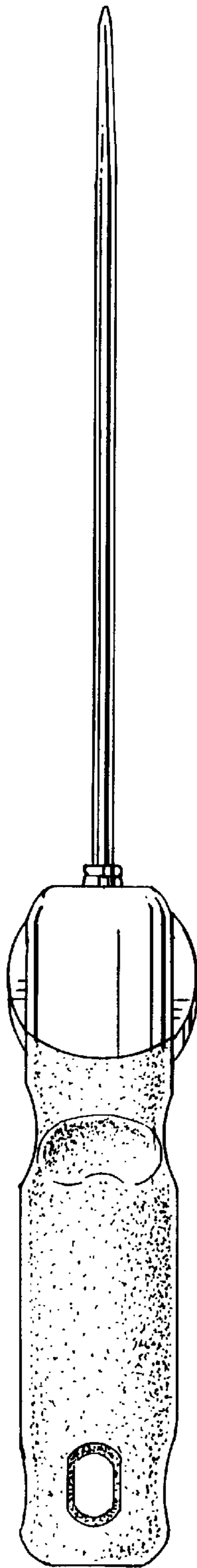
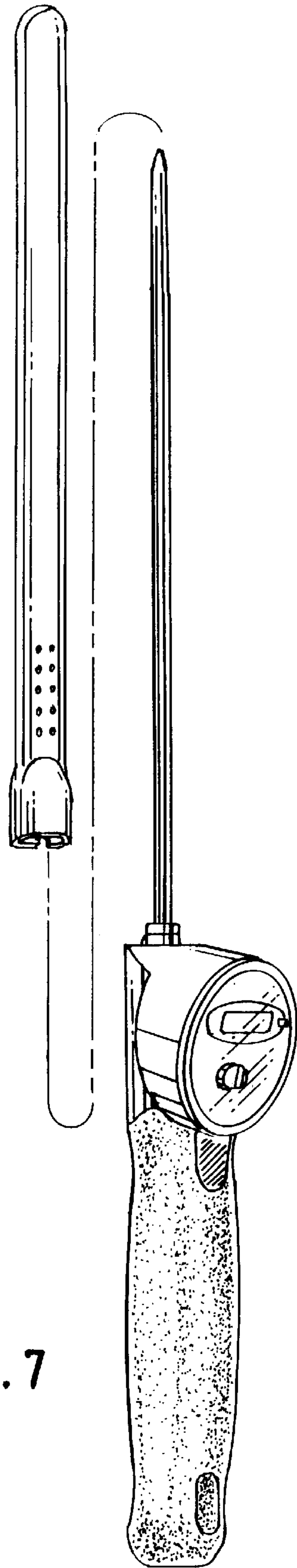


FIG. 7



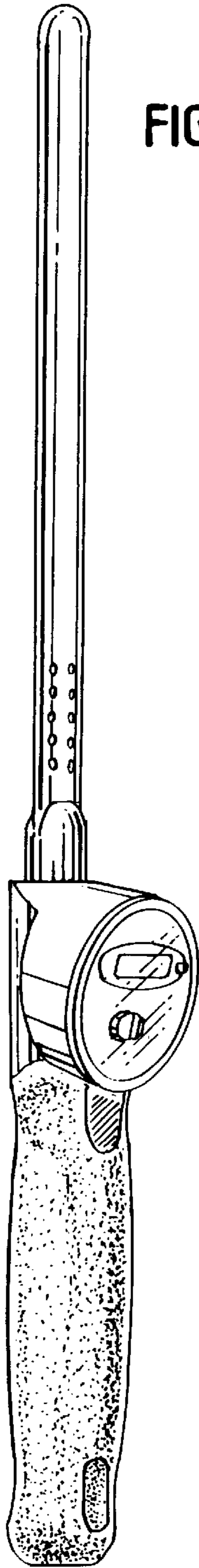


FIG. 8

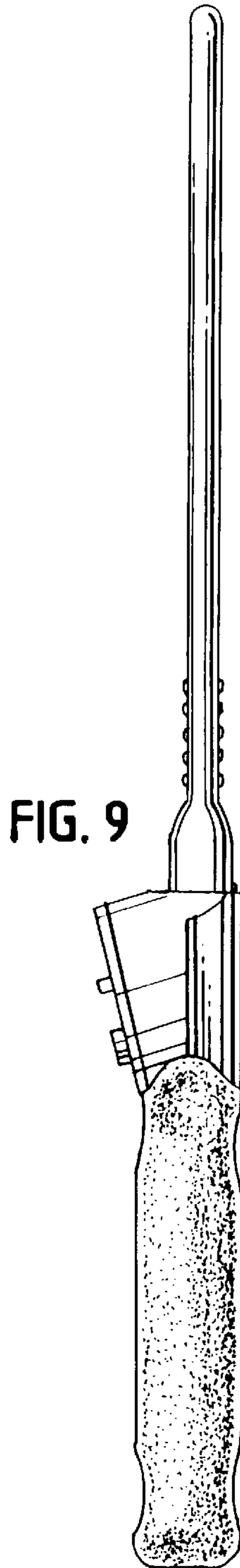


FIG. 9

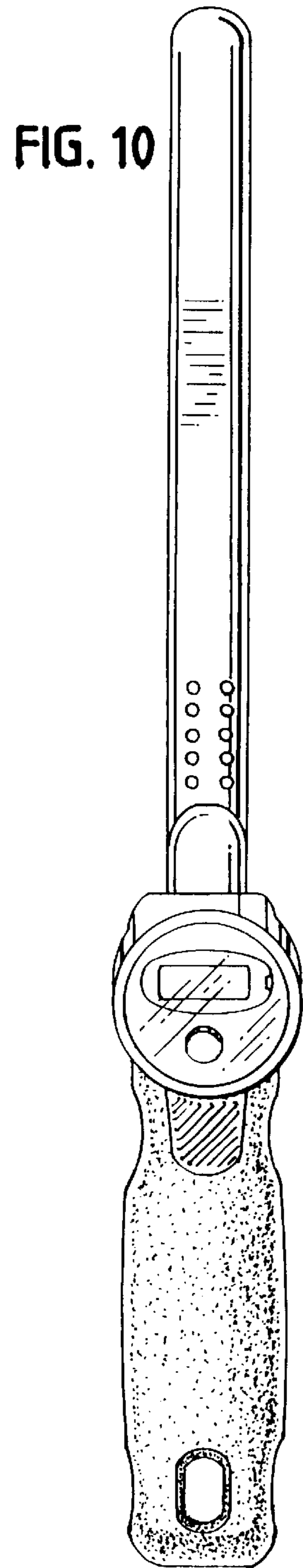


FIG. 10

FIG. 11

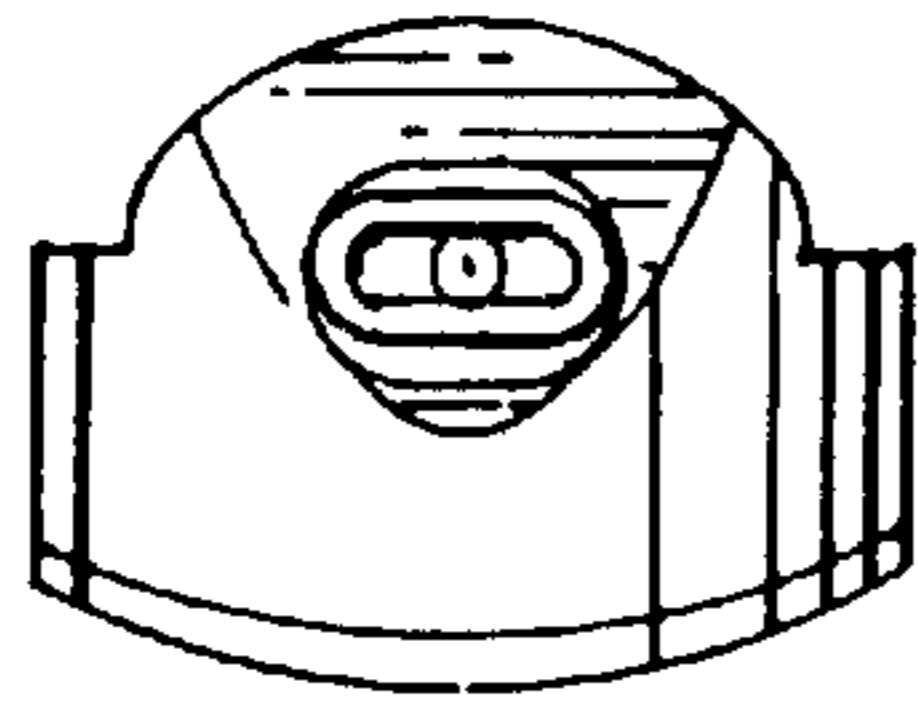


FIG. 12

